



AI Test

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Message from the Guest Editors

Dear Colleagues,

Topics of interest include, but are not limited to:

- Quality models, quality attributes and metrics for AI applications, such as robustness, fairness, reliability and performance.
- Testing methods, techniques and tools for various aspects and activities of testing and quality assurance, especially for test case generation, test oracle, and test adequacy measurements.
- Test automation environment and platforms for AI applications and by employing AI techniques.
- Domain specific testing techniques and methods for various special domains of AI applications, such as AI applications in natural language processing such as ChatGPT, image recognitions, time series and Internet of Things data analysis, medical and healthcare, robotics, software code generation/debugging/design, etc.
- Testing and quality assurance for various specific AI techniques, such as clusters and classifiers, regression machine learning models, deep neural networks, big models, recurrent neural networks, etc.





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Message from the Editor-in-Chief

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